Docket No.: 50090-332

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In the Application of

Customer Number: 20277

Hisaya MORI, et al.

Confirmation Number: 4507

Serial No.: 09/927,368

Group Art Unit: 2829

Filed: August 13, 2001

Examiner: Chan, Emily Y.

For:

APPARATUS AND METHOD FOR TESTING SEMICONDUCTOR INTEGRATED CIRCUIT

Mail Stop Non-Fee Response Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Transmitted herewith is a Request for Reconsideration in the above-identified application.

No additional fee is required.

Applicant is entitled to small entity status under 37 CFR 1.27

Also attached:

The fee has been calculated as shown below:

| | NO. OF CLAIMS | HIGHEST PREVIOUSLY PAID FOR | EXTRA CLAIMS | RATE | FEE |
|--------------------|------------------|-----------------------------------|-----------------------------|-----------|--------|
| Total Claims | 11 | 20 | 0 | \$18.00 = | \$0.00 |
| Independent Claims | 2 | 3 | 0 | \$86.00 = | \$0.00 |
| | | Multiple claims newly presented | | | \$0.00 |
| | | Fee for extension of time | | | \$0.00 |
| | | | | | \$0.00 |
| | | | Total of Above Calculations | | |

Please charge my Deposit Account No. 500417 in the amount of \$0.00. An additional copy of this transmittal sheet is submitted herewith.

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The Commissioner is hereby authorized to charge payment of any fees associated with this communication or credit any overpayment, to Deposit Account No. 500417, including any filing fees under 37 CFR 1.16 for presentation of extra claims and any patent application processing fees under 37 CFR 1.17.

Respectfully submitted,

MCDERMOTT, WILL & EMERY

Alexander V. Yampolsky Registration No. 36,324

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Facsimile: (202) 756-8087 Date: November 6, 2003 WDC99 837263-1.057454.0903

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CIRCUIT

REQUEST FOR RECONSIDERATION

Mail Stop Non-Fee Response Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

This Request is submitted in response to the Office Action mailed August 7, 2003.